

Review: ISO 13099 Colloidal systems — Methods for zeta potential determination

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[ISO 13099-1:2012](#)

Colloidal systems -- Methods for zeta-potential determination -- Part 1: Electroacoustic and electrokinetic phenomena



[ISO 13099-2:2012](#)

Colloidal systems -- Methods for zeta-potential determination -- Part 2: Optical methods



[ISO/NP 13099-3](#)

Methods for zeta potential determination -- Part 3: Acoustic methods



[Standards under development](#)

Outline

- ISO standards
- Zeta potential background
- Cells
- Operational and dilution procedures
- Reference materials
- System verification

ISO TC 24/SC 4 Published Standards

TC 24/SC 4 - Particle characterization
32 standards published so far_

ISO 9276:1998 Representation of results of particle size analysis

Part 1: Graphical representation

Part 2: Calculation of average particle sizes/diameters and moments from particle size distributions

Part 3: Adjustment of an experimental curve to a reference model

Part 4: Characterization of a classification process

Part 5: Methods of calculation relating to particle size analyses using logarithmic normal probability distribution

Part 6: Descriptive and quantitative representation of particle shape and morphology

ISO 9277:2010 Determination of the specific surface area of solids by gas adsorption

-- BET method

ISO 13099-1:2012 Colloidal systems -- Methods for zeta-potential determination

Part 1: Electroacoustic and electrokinetic phenomena

Part 2: Optical methods

ISO TC 24/SC 4 Published Standards

ISO 13317-1:2001: **Determination of particle size distribution by gravitational liquid sedimentation methods**

Part 1: General principles and guidelines

Part 2: Fixed pipette method

Part 3: X-ray gravitational technique

ISO 13318-1:2001: **Determination of particle size distribution by centrifugal liquid sedimentation methods**

Part 1: General principles and guidelines

Part 2: Photocentrifuge method

Part 3: Centrifugal X-ray method

ISO 13319:2007 **Determination of particle size distributions -- Electrical sensing zone method**

ISO 13320:2009 **Particle size analysis -- Laser diffraction methods**

ISO 13321:1996 Particle size analysis -- **Photon correlation spectroscopy**

ISO 13322-1:2004 Particle size analysis -- **Image analysis methods**

Part 1: Static image analysis methods

Part 2: Dynamic image analysis methods

ISO TC 24/SC 4 Published Standards

ISO 14488:2007 Particulate materials -- **Sampling and sample splitting for the determination of particulate properties**

ISO 14887:2000 Sample preparation -- **Dispersing procedures for powders in liquids**

ISO 15900:2009 Determination of particle size distribution -- **Differential electrical mobility analysis for aerosol particles**

ISO 15901-1:2005 **Pore size distribution and porosity of solid materials by mercury porosimetry and gas adsorption**

Part 1: Mercury porosimetry

Part 2: Analysis of mesopores and macropores by gas adsorption

Part 3: Analysis of micropores by gas adsorption

ISO 20998-1:2006 **Measurement and characterization of particles by acoustic methods**

Part 1: Concepts and procedures in ultrasonic attenuation spectroscopy

ISO TC 24/SC 4 Published Standards

ISO 21501-1:2009 **Determination of particle size distribution Single particle light interaction methods**

Part 1: Light scattering aerosol spectrometer

Part 2: Light scattering liquid-borne particle counter

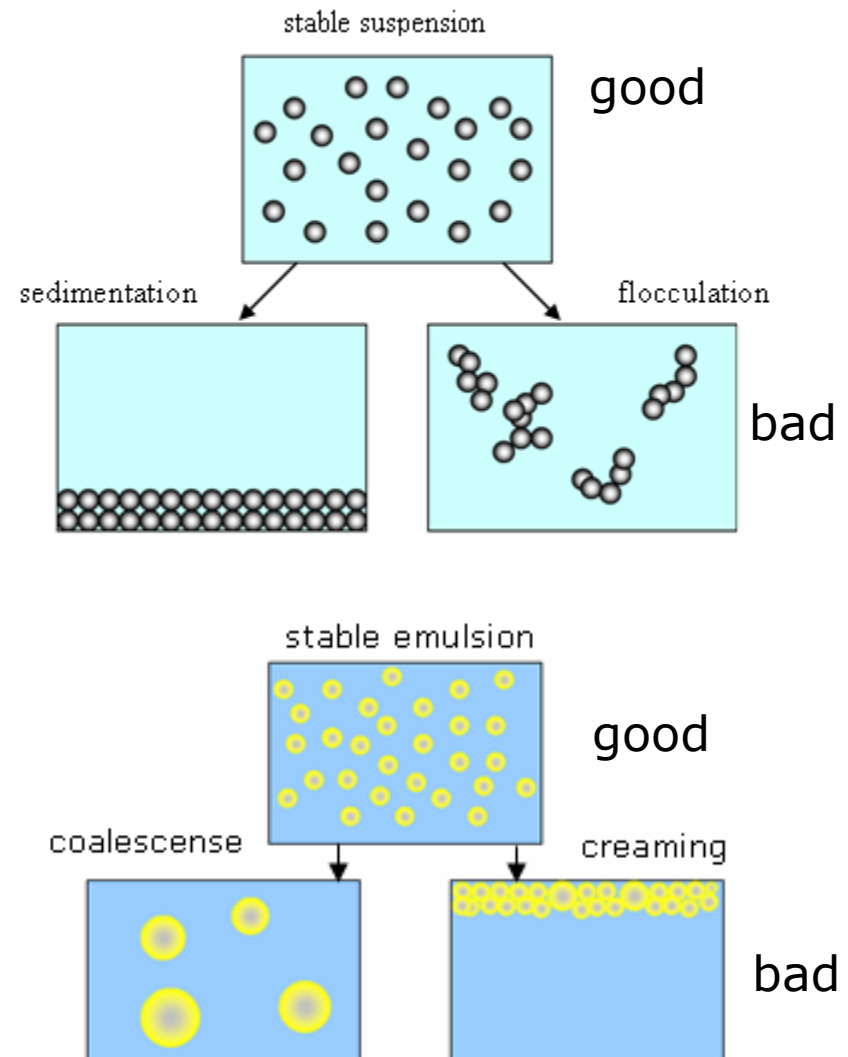
Part 3: Light extinction liquid-borne particle counter

Part 4: Light scattering airborne particle counter for clean spaces

ISO 22412:2008 **Particle size analysis -- Dynamic light scattering (DLS)**

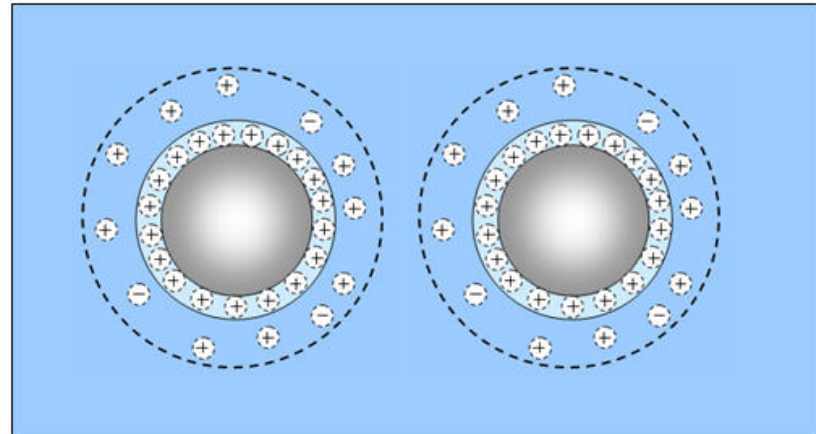
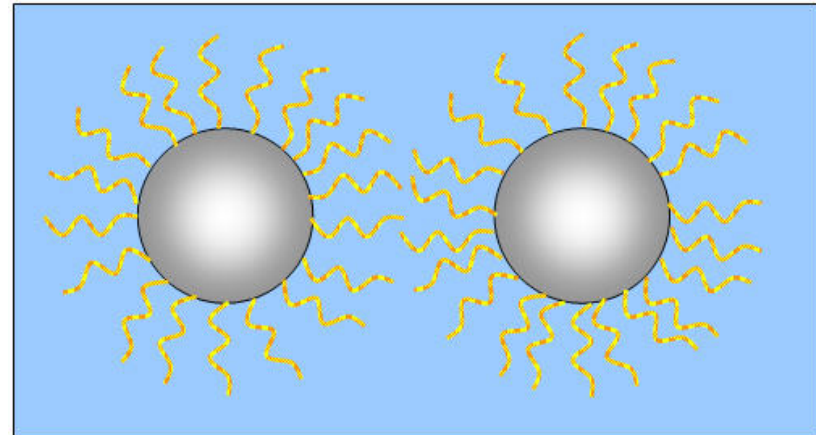
Why Colloidal Systems?

- Zeta potential often used in colloidal stability studies
- Want stable dispersion
- Suspensions sediment & flocculate
- Emulsions phase separate, creaming or coalescence



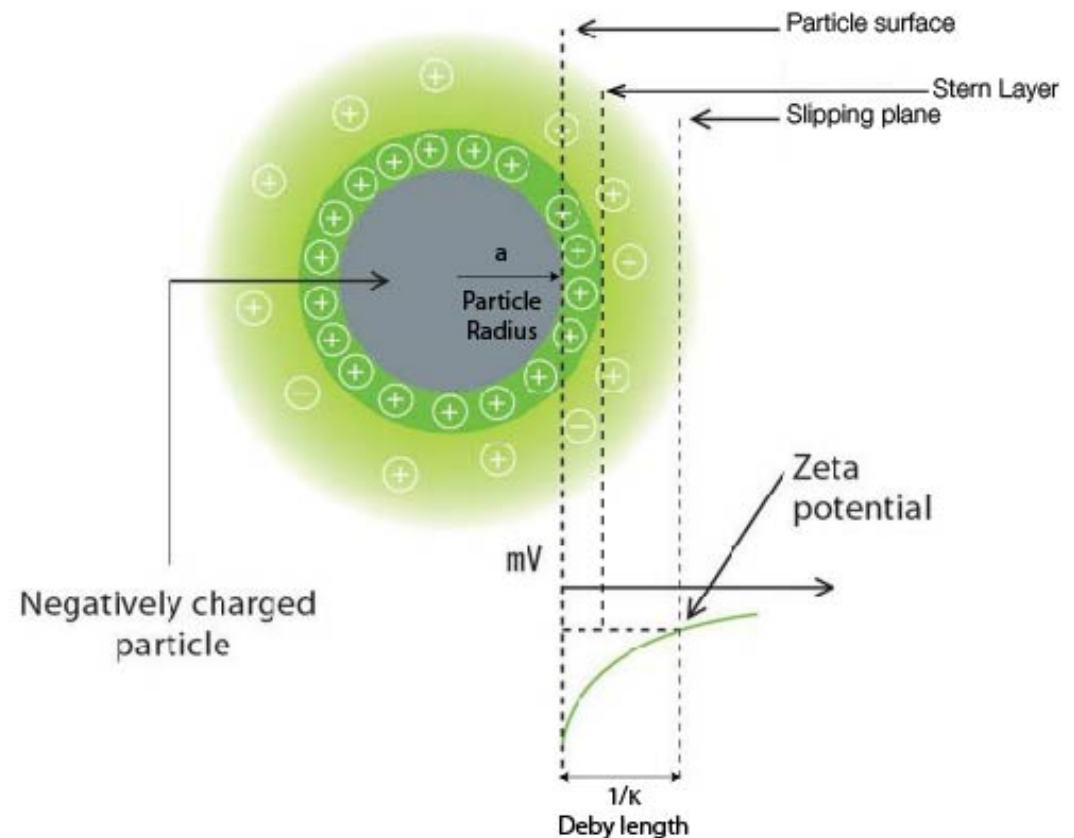
Stabilization

- Steric stabilization: coat surface with polymers
- Particles can't touch so they don't interact
- Electrostatic stabilization: alter surface chemistry to put charge on particle surface
- Repel like magnets



Zeta Potential

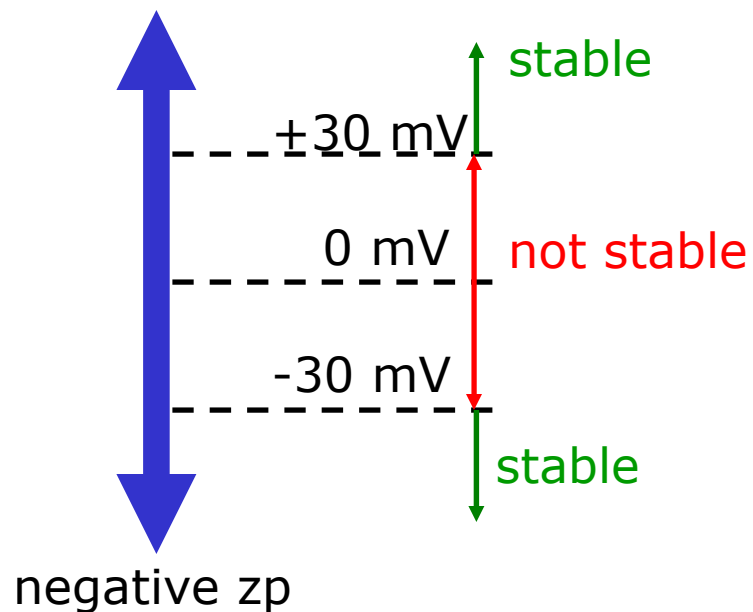
- If surface has - charge, then + ions attracted to surface
- - ions attracted to + ions, builds electric double layer
- Slipping plane: distance from particle surface where ions move with particle
- ZP = potential (mV) at slipping plane



Zeta Potential Predicts Stability

Different guidelines

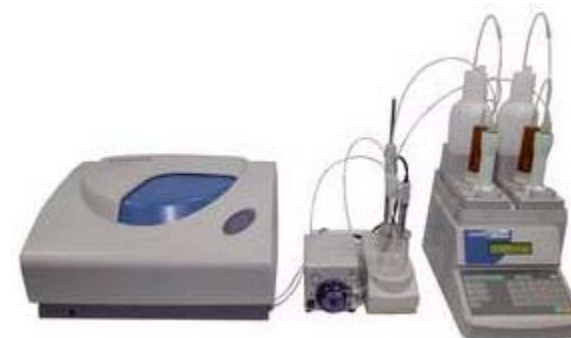
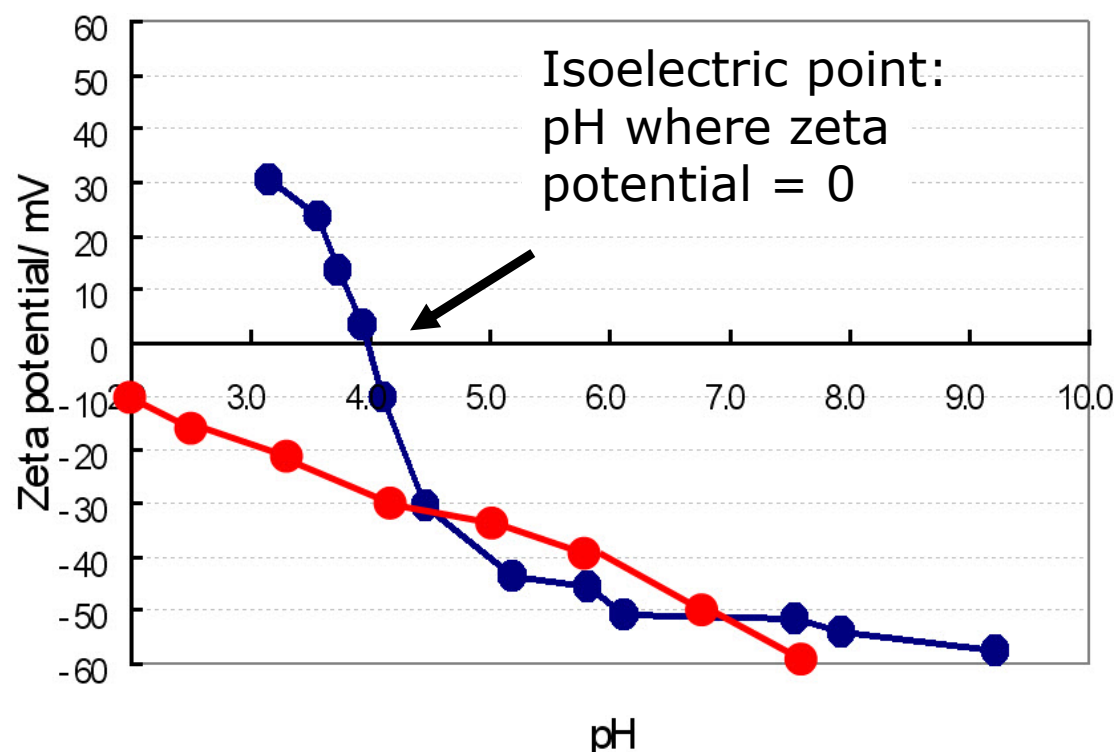
positive zp



Sample Dependency

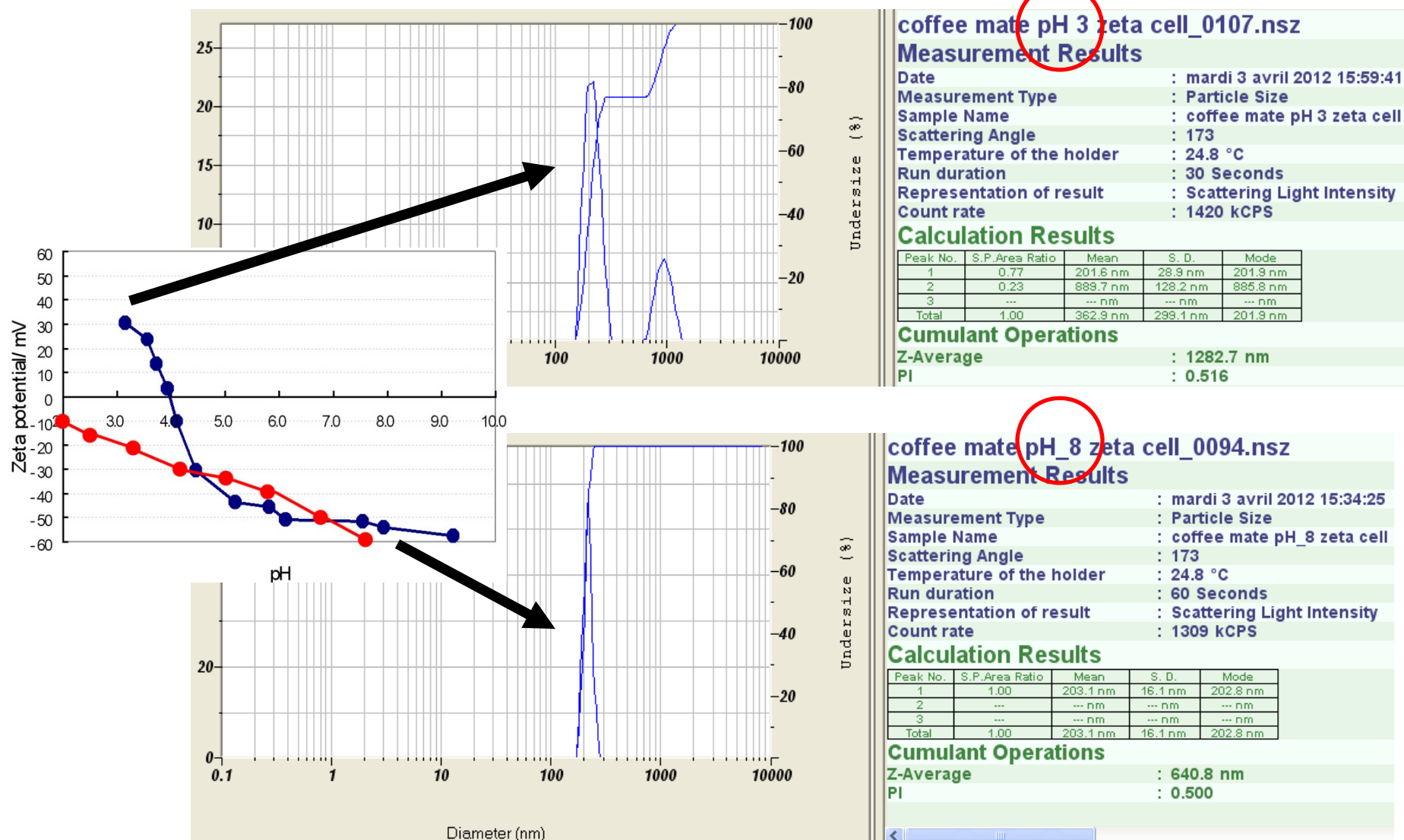
- Oil/water emulsions > 10 mV
- Polymer latices > 15 mV
- Oxides > 30 mV
- Metal sols > 40 mV

Zeta Potential: Emulsion Isoelectric Point (IEP)



Automate IEP
studies with
auto titrator

Emulsion IEP Study: Stability



Zeta Potential: Measurement

■ Optical

● Microscope



● Electrophoretic light scattering – (ELS)

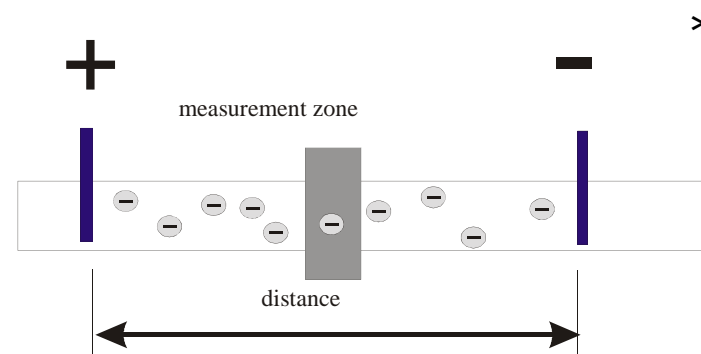


■ Acoustic



Zeta Potential: ELS Measurement

- Apply electric field
- Measure particle motion
- Direction tells + or –
 - + particles move to –
 - - particles move to +
- Speed tells amplitude
 - Get speed from frequency shift from motion of particles



* Figure 1, part 2

Optical Configuration

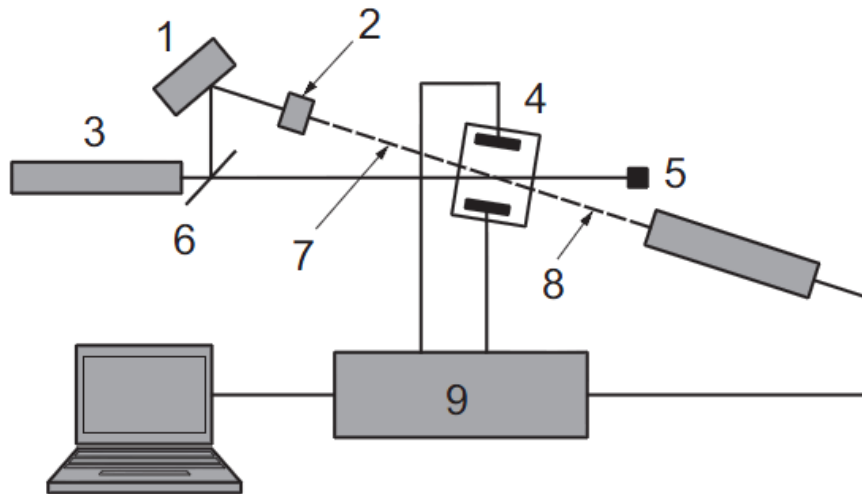
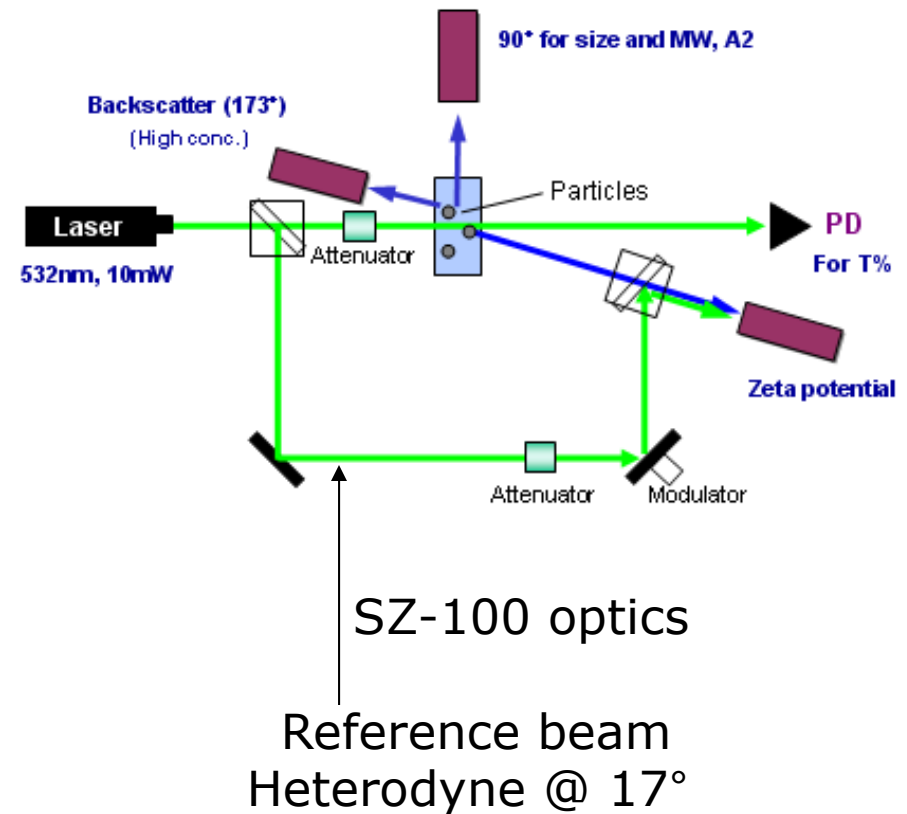
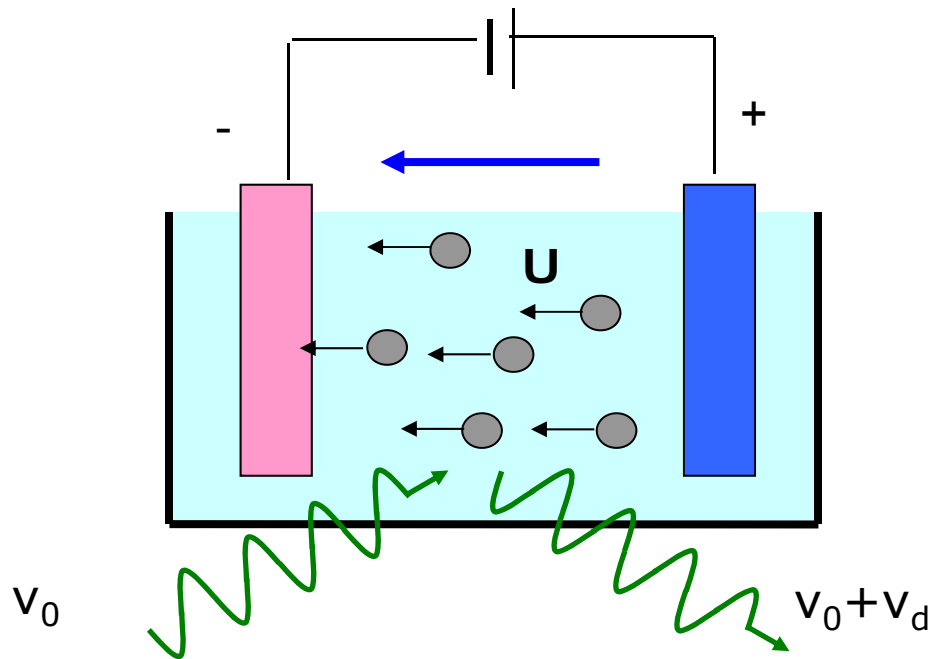


Figure 3 from 13099-2*



* Figure 3, part 2

Zeta Potential Measurement



Mobility*

$$\mu = \frac{\Delta\omega\lambda_0}{4\pi n E \sin(\theta/2) \sin[(\theta/2) + \xi]}$$

Zeta potential*

$$\mu = \frac{2\zeta\epsilon}{3\eta_0} f(\kappa a)$$

Particle motion causes Doppler shift
 Frequency → mobility
 Mobility → zeta potential

μ	electrophoretic mobility
$\Delta\omega$	Doppler frequency shift
λ_0	laser wavelength
n	medium refractive index
E	electric field strength
θ	angle between incident & scattered light
ζ	zeta potential
ϵ	dielectric permittivity
η_0	medium viscosity
$f(\kappa a)$	ratio of the particle radius to the EDL

* Equations 1 and 2, part 2, section 6.6

Thin vs. Thick Double Layer

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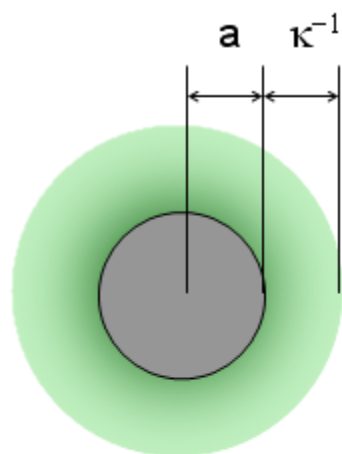
$$\mu = \frac{2\zeta\epsilon}{3\eta_0} f(\kappa a)$$

Debye length $= \kappa^{-1}$

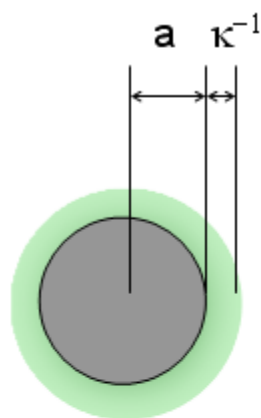
Particle radius $= a$

Viscosity $= \eta$

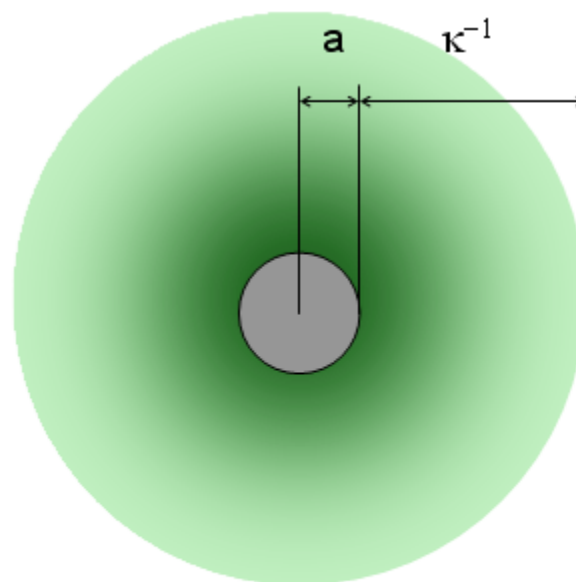
Dielectric permittivity $= \epsilon$



Huckel
 $F(\kappa a) = 1.0$



thin double layer
Smoluchowski
 $F(\kappa a) = 1.5$
 $\kappa a \gg 1$



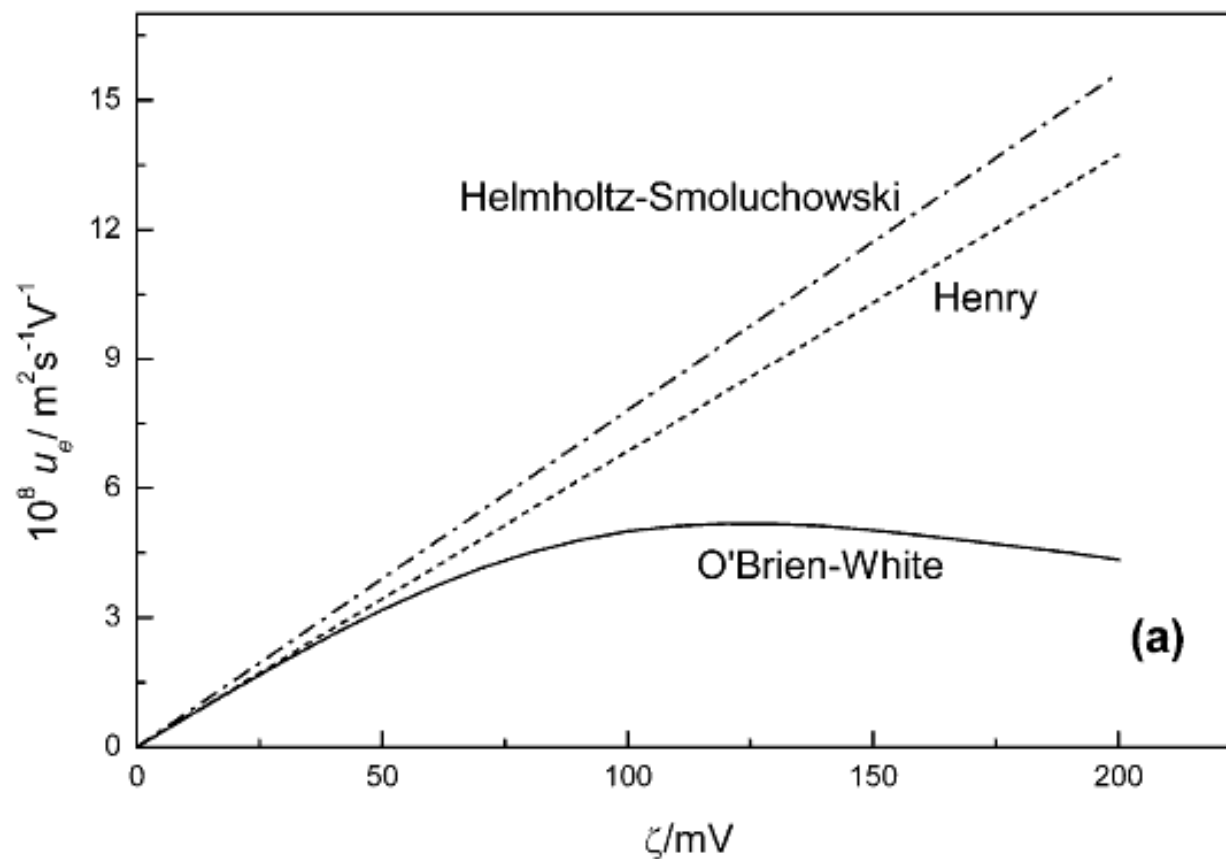
thick double layer
 $\kappa a \ll 1$

SZ-100 Software

- Default is Smoluchowski
- Selection for Huckel
- Or enter manually for other model

Sample Information	Particle/Dispersion Medium	Measurement	Cell	Calculation	Reports	Automatic Save
Select dispersion medium, material and other sample properties						
Particle	: mono-polystyrene	Sample List				
Dispersion Medium	: Water	Dispersion Medium List				
Refractive Index of the Dispersion Medium	: 1.333					
Viscosity of the Dispersion Medium	: $\eta = (2.6325758 \times 10^{-8})T^4 - (3.6103169 \times 10^{-5})T^3 + (1.8631000 \times 10^{-2})T^2 - 4.2933532T + (3.7362098 \times 10^2)$					
Temperature	: --- °C					
Dielectric Constant	: $\epsilon_r = (-1.410000 \times 10^{-6})T^3 + (2.095200 \times 10^{-3})T^2 - 1.229100T + (2.958800 \times 10^2)$					
Henry Coefficient	Manual <input type="text" value="0.75"/>					

Advanced Theories*

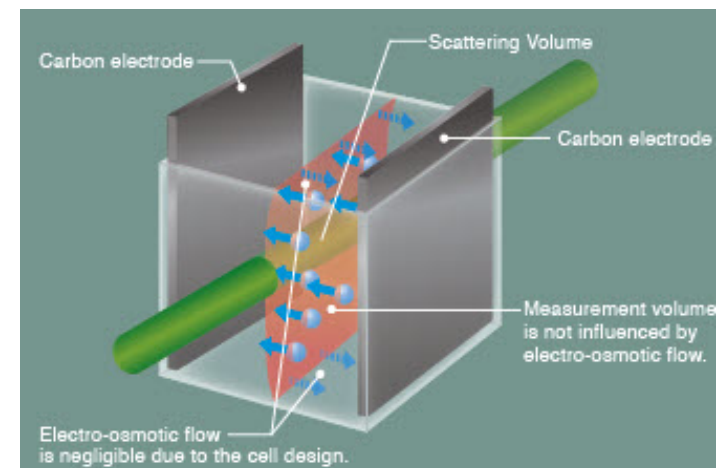
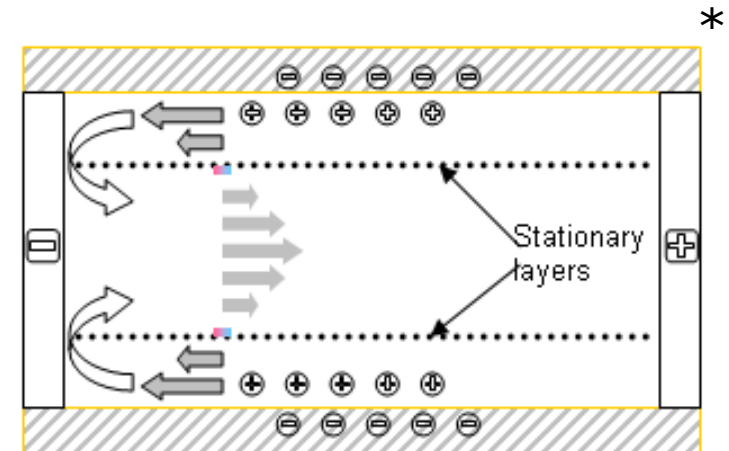


* Discussed in part 1, but graph from IUPAC technical report **MEASUREMENT AND INTERPRETATION OF ELECTROKINETIC PHENOMENA** *Pure Appl. Chem.*, Vol. 77, No. 10, pp. 1753–1805, 2005

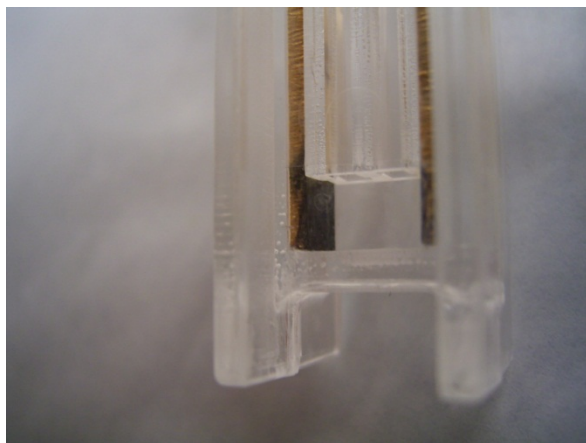
Measurement Details

- First measure conductivity
 - Auto or manually
- Then decide applied electric field
- Reverse electric field to avoid polarization & electroosmosis
- To avoid electroosmotic effect near cell walls
 - “Uzgiris” type cells avoid this problem

* Figure 6, part 2



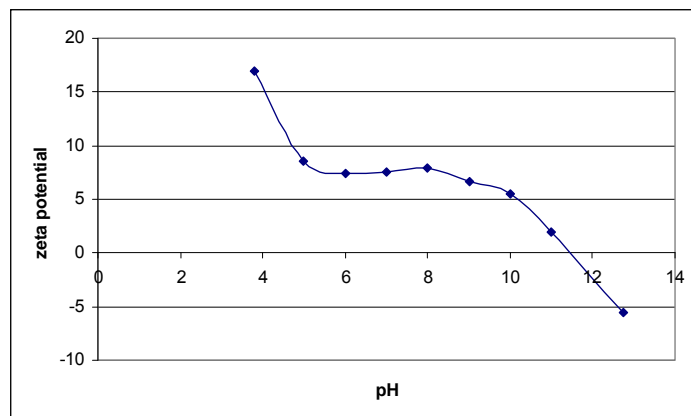
Zeta Potential Cells



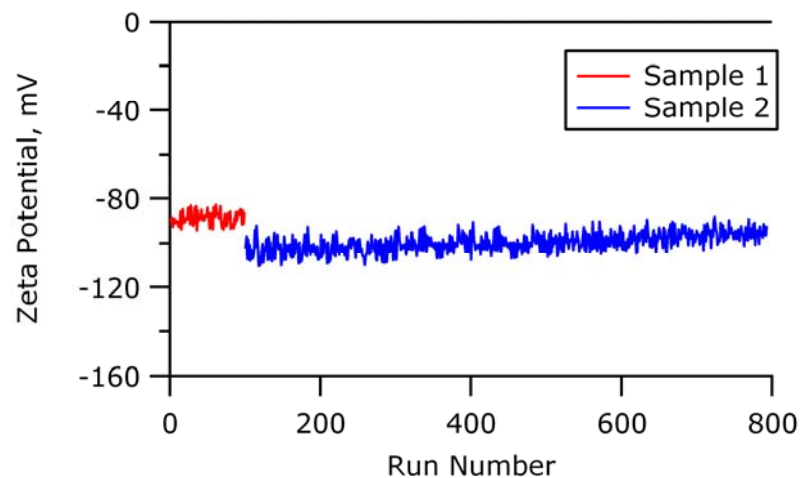
Gold coated electrodes (ruined)



Carbon coated electrodes



IEP 3.4 nm protein



800 measurements with one cell

Section 8 Operational Procedures

- **Instrument location** Place the instrument in a clean environment on a surface without vibration
- **Dispersion liquids** Ensure chemical compatibility between the medium and the cell
- **Measurement cell** Clean cells that have been previously used, control the temperature
- **Sample inspection** Look for sedimentation, if visible then the measurement is questionable

Section 8: Dilution

- Try to avoid dilution
- Don't dilute with DI water
 - No ions, changes surface chemistry & ZP
- Best: equilibrium dilution with same liquid as sample, but with no particles
 - Us supernatant after sedimentation →
or centrifugation
- Otherwise, dilute with 0.01 M KCL solution



Section 8.2: Verification

- 8.2.1 reference Materials
- Be sufficiently homogeneous and stable for the stated time and temperature range
- The accepted electrophoretic mobility value was obtained by several operators and rigorously proven.
- The material should be well documented in terms of sampling procedure, dilution, if required, and measurement protocol.

Section 8.2: Verification

- **8.2.2 Repeatability**
- Prepare sample following provided procedure
- Measure same portion three times
- Pass if mean value CV <10%
 - Assuming $2 \times 10^{-8} \text{ m}^2/\text{V}\cdot\text{s}$
- Note: expect most customers to use zeta potential values

Section 8.2: Verification

- **8.2.3 Intermediate Precision**
- Same procedure as 8.2.2 but using different portions of sample
- Pass if Repeatability; $CV < 15\%$
 - Assuming $2 \times 10^{-8} \text{ m}^2/\text{V}\cdot\text{s}$
- Doubt this is done often
- In pharmaceutical industry intermediate precision implies multiple systems, multiple operators, different days

Section 8.2: Verification

- **8.2.4 Trueness** (accuracy)
- Prepare, measure same portion 3 times
- Pass if mean value within 10% of published electrophoretic mobility value, assuming $> 2 \times 10^{-8} \text{ m}^2/\text{V}\cdot\text{s}$.
- Note: when calculating pass/fail criteria it is OK to include the uncertainty of the sample
- Note: most customers use the zeta potential value, not the mobility

NIST SRM1980 on SZ-100

Pass criteria:

Mean within 10% of reference value

COV < 10%

Reference value

$2.53 \mu\text{m}\cdot\text{cm}/\text{V}\cdot\text{s} \pm 0.12 \mu\text{m}\cdot\text{cm}/\text{V}\cdot\text{s}$

Upper limit:

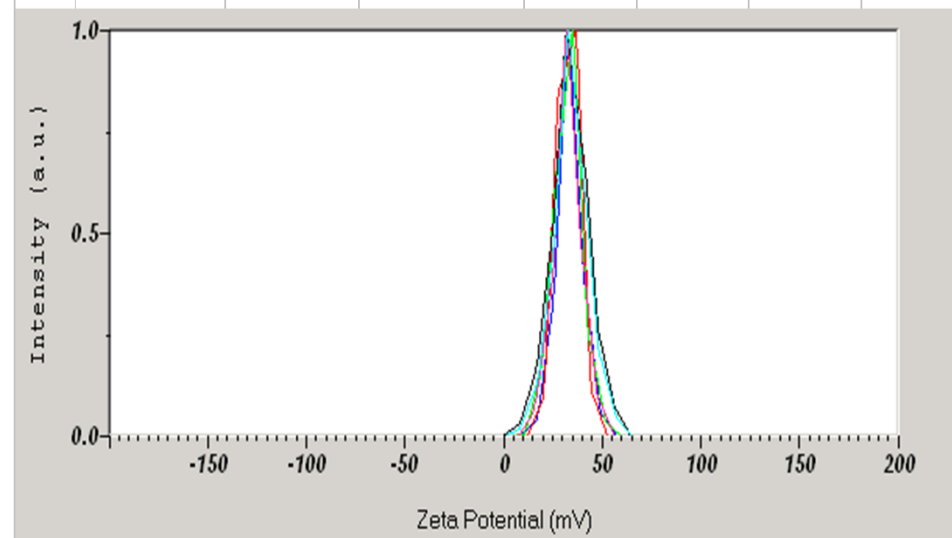
$(2.53 + 0.12) \cdot 1.1 = 2.92$

Lower limit:

$(2.53 - 0.12) \cdot 0.9 = 2.17$

Pass

No.	Sample Name	Zeta Potential(mV)	Electrophoretic Mobility(cm ² /Vs)				
17	NIST SRM1980	33,4	0,000257				
18	NIST SRM1980	32,7	0,000252				
19	NIST SRM1980	32,5	0,00025				
20	NIST SRM1980	33,9	0,000261				
21	NIST SRM1980	32,7	0,000252				
22	NIST SRM1980	34,2	0,000263				
Mean		33,2	0,000256				
S. D.		0,7	0,000005				
COV		2,11	1,95				



Section 8.3: Sources of Error

- Contamination from previous sample
- Poor sample preparation
- Inappropriate sample
- Inappropriate liquid medium
- Poor temperature stabilization
- Condensation on the illuminated surfaces
- Too large a potential applied

Section 8.3: Sources of Error

- Particles, fingerprints or scratches on the optical surfaces
- Incorrect entry of parameters by the operator
- Air bubbles
- Cell coating damage
- Inappropriate theory for calculating zeta-potential from the measured electrophoretic mobility

Summary

- ISO 13099 part 1 and 2 useful for chemists new to zeta potential
- Some theoretical background
- Some operational advice
- Agreed upon pass/fail verification
 - But most customers use zeta potential, not electrophoretic mobility
- How we suggest you comply: use an SZ-100 from HORIBA
 - Best cells, lower cost of ownership

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Particle Characterization

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HORIBA offers instruments for particle size, particle shape, zeta potential, and surface area analysis. Measurable particle size range is from 1 nanometer to 30 millimeters, at concentrations ranging from 1 ppm to 50 vol% with shape determination available starting at 1 micrometer. A range of analytical techniques are employed including laser diffraction (Mie Theory), dynamic light scattering, acoustic and electroacoustic spectroscopy, and dynamic and static image analysis. (measuring both particle size and shape information).

HORIBA's advanced designs and powerful software, combined with flexible sample handling systems are available to meet every analysis need. These instruments can incorporate small volume pumping systems for precious materials, high throughput automation, dry powder dispersers and temperature controlled flow systems in order to provide the user with the best possible solution with none of the trade-offs that might otherwise be necessary.

Particle Size

- ▣ Laser diffraction
 - ▣ LA-950V2
 - ▣ LA-300
- ▣ Dynamic light scattering
 - ▣ SZ-100

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